



## N-Channel Enhancement MOSFET

### Features

- Drain-Source Breakdown Voltage  $V_{DS}$  30 V
- Drain-Source On-Resistance
- $R_{DS(ON)}$  25m $\Omega$ , at  $V_{GS}= 10V$ ,  $I_D=4.0A$   
 $R_{DS(ON)}$  36m $\Omega$ , at  $V_{GS}= 4.5V$ ,  $I_D= 3.5A$
- Continuous Drain Current at  $T_A=25^\circ C$   $I_D = 4.7A$
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free

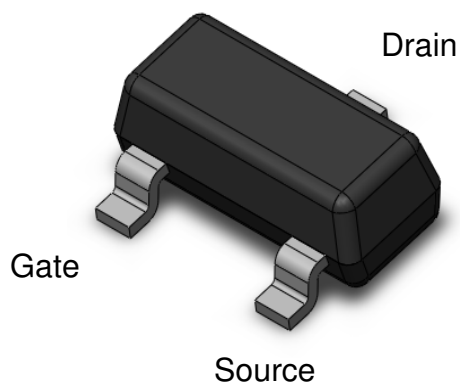
### Description

The CT2306-R3 uses high performance Trench Technology to provide excellent  $R_{DS(ON)}$  and low gate charge which is suitable for most of the synchronous buck converter applications.

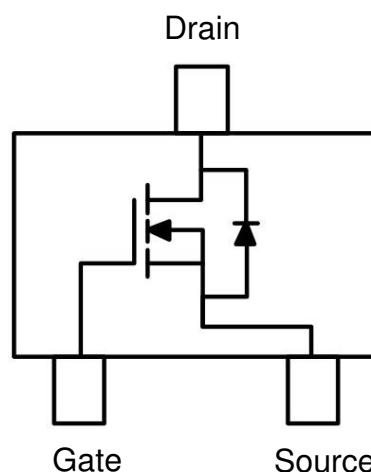
### Applications

- Power Management
- DC-DC Converter
- Load Switch

### Package Outline



### Schematic



**Absolute Maximum Rating at 25°C**

Symbol	Parameters	Test Conditions	Min	Notes
V <sub>DS</sub>	Drain-Source Voltage	30	V	
V <sub>GS</sub>	Gate-Source Voltage	±20	V	
I <sub>D</sub>	Continuous Drain Current @T <sub>A</sub> =25°C	4.7	A	1
I <sub>DM</sub>	Pulsed Drain Current	20	A	1
P <sub>D</sub>	Total Power Dissipation @T <sub>A</sub> =25°C	1.3	W	2
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C	
T <sub>J</sub>	Operating Junction Temperature Range	-55 to 150	°C	

**Thermal Characteristics**

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
R <sub>θJA</sub>	Thermal Resistance Junction-Ambient		--	125	--	°C /W	1,4



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**Electrical Characteristics**  $T_A = 25^\circ\text{C}$  (unless otherwise specified)

**Static Characteristics**

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
B <sub>VDS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	30	-	-	V	
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V	-	-	1	μA	
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V	-	-	±100	nA	

**On Characteristics**

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
R <sub>DS(ON)</sub>	Drain-Source On-Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 4.0A	-	25	45	mΩ	3
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 3.5A	-	36	50	mΩ	
V <sub>GS(th)</sub>	Gate-Source Threshold Voltage	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 250μA	1.0	---	3.0	V	3

**Dynamic Characteristics**

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
C <sub>ISS</sub>	Input Capacitance	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 15V f = 1MHz	-	382	-	pF	
C <sub>OSS</sub>	Output Capacitance		-	65	-		
C <sub>RSS</sub>	Reverse Transfer Capacitance		-	16	-		

**Switching Characteristics**

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
T <sub>D(ON)</sub>	Turn-On Delay Time	V <sub>DS</sub> = 15V , V <sub>GS</sub> = 10V, R <sub>G</sub> = 3Ω, I <sub>D</sub> = 3.4A	-	9	-	ns	Fig 8 & 9
T <sub>R</sub>	Rise Time		-	15	-		
T <sub>D(OFF)</sub>	Turn-Off Delay Time		-	32	-		
T <sub>F</sub>	Fall Time		-	3	-		
Q <sub>G</sub>	Total Gate Charge	V <sub>DS</sub> = 15V , V <sub>GS</sub> = 15V, I <sub>D</sub> = 3.4A	-	6.4	-	nC	Fig 6 & 7
Q <sub>GS</sub>	Gate-Source Charge		-	3	-		
Q <sub>GD</sub>	Gate-Drain (Miller) Charge		-	2.5	-		



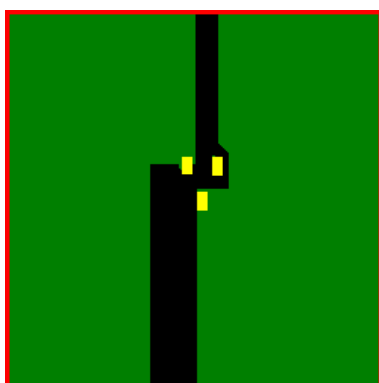
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### Drain-Source Diode Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
V <sub>SD</sub>	Body Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 4.7	-	-	1.2	V	
I <sub>SD</sub>	Body Diode Continuous Current		-	-	4.7	A	1

Note:

1. The power dissipation is limited by 150°C junction temperature.
2. Device mounted on a glass-epoxy board



FR-4  
25.4 × 25.4 mm .  
2 Oz Copper

Actual Size

3. The data tested by pulsed , pulse width  $\leq 300\mu\text{s}$  , duty cycle  $\leq 2\%$
4. Thermal Resistance follow JESD51-3.



### Typical Characteristic Curves

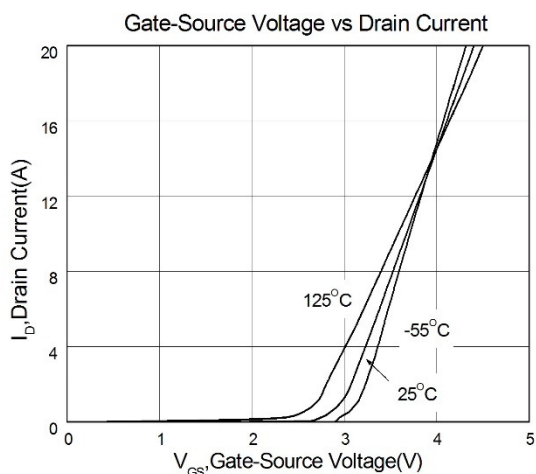


Figure 1

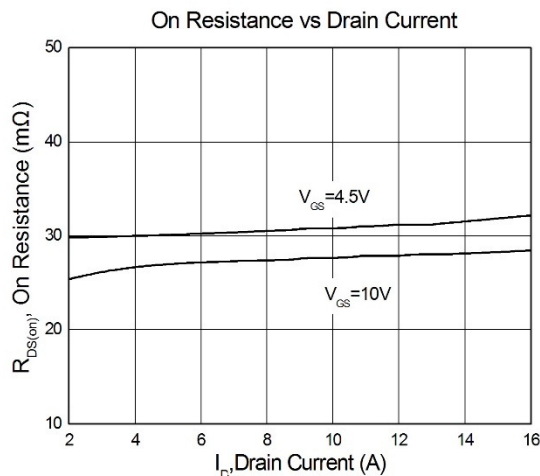


Figure 2

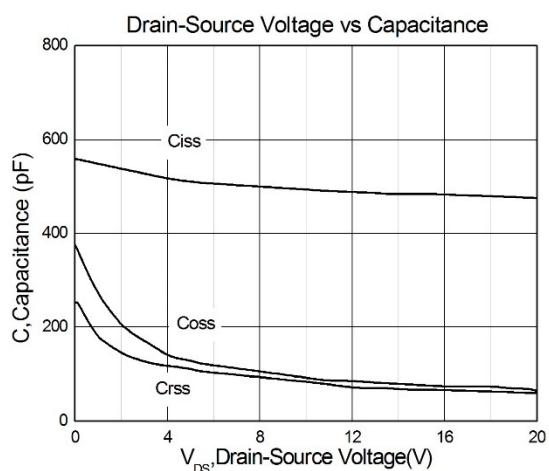


Figure 3

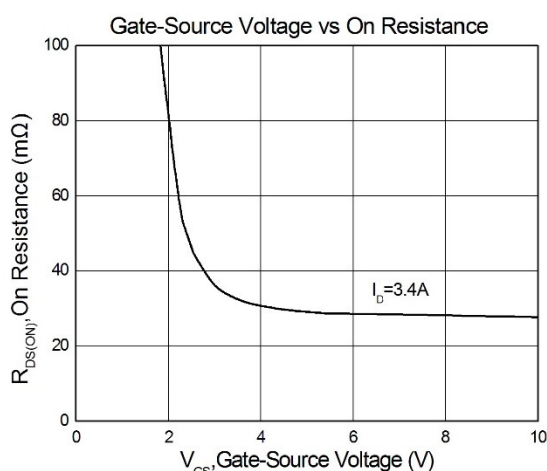


Figure 4

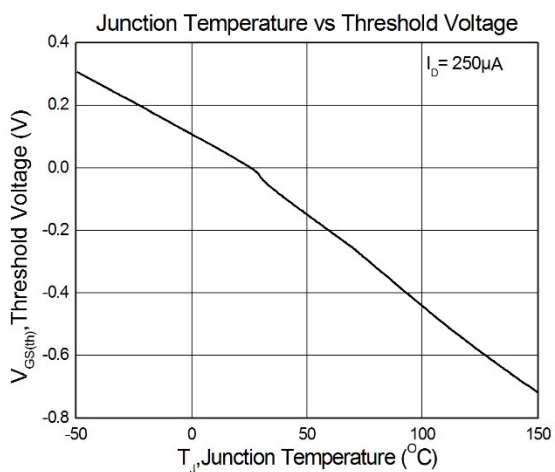


Figure 5



Test Circuits & Waveforms

Figure 9: Gate Charge Test Circuit

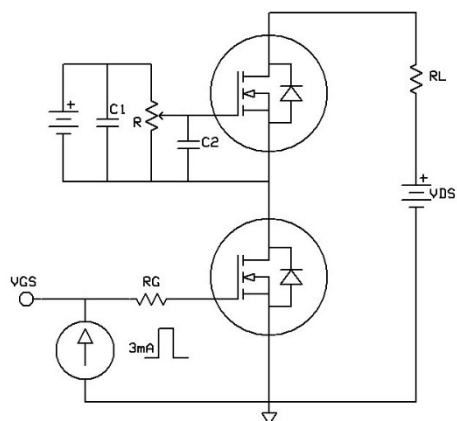


Figure 10: Gate Charge Waveform

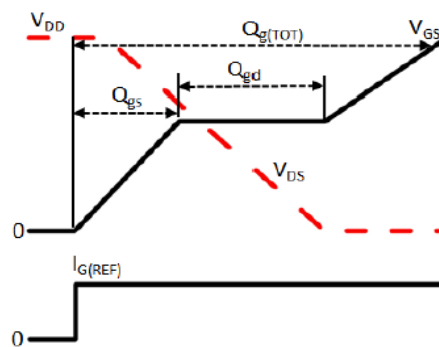


Figure 11: Switching Time Test Circuit

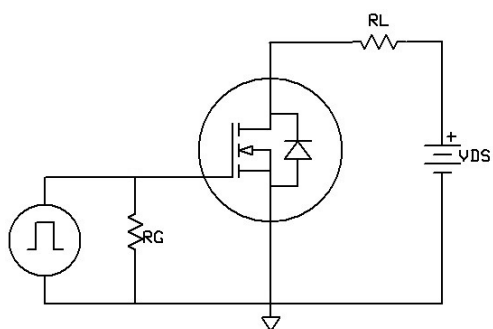
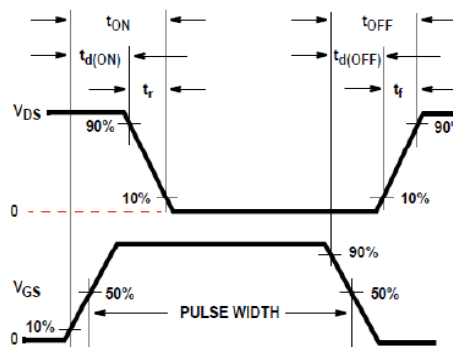
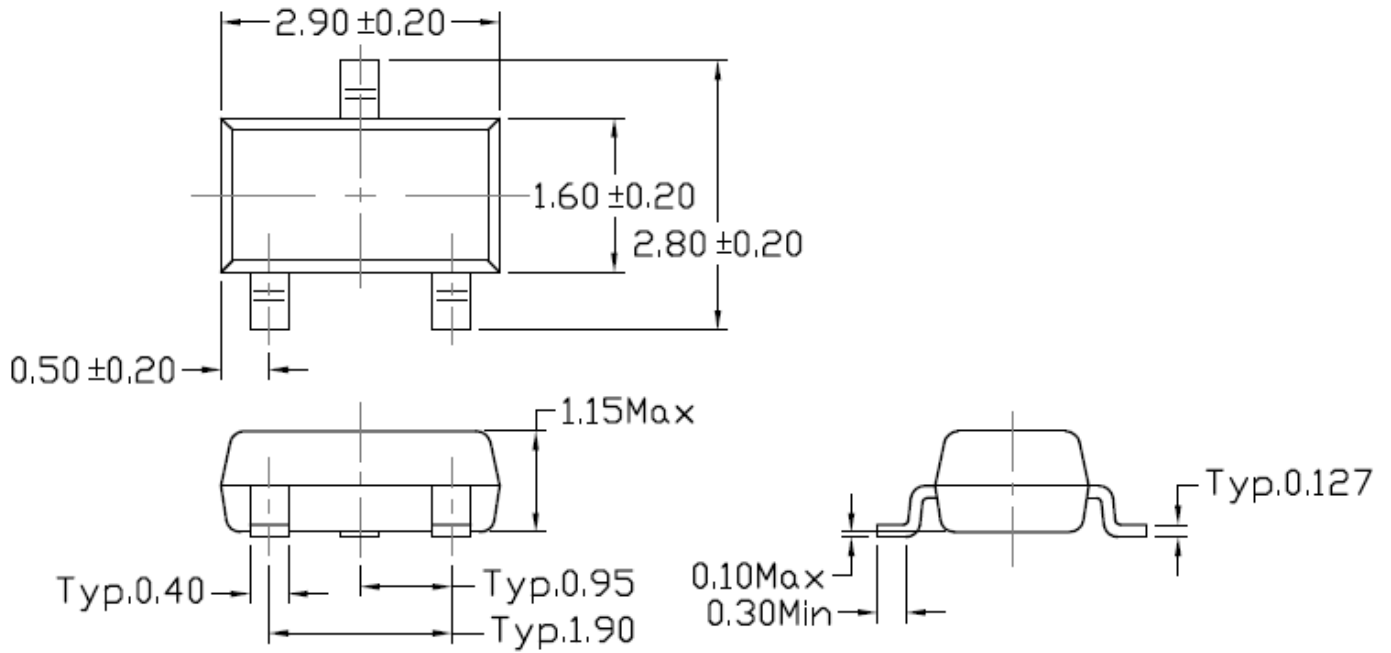


Figure 12: Switching Time Waveform



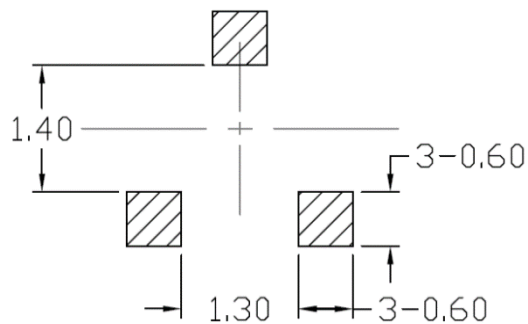


Package Dimension (SC-59)



Note: Dimensions in mm

Recommended pad layout for surface mount leadform



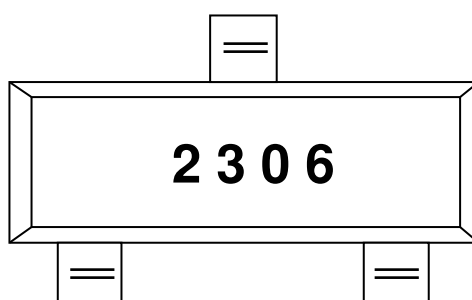
Note: Dimensions in mm



CT2306-R3

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### Marking Information



2306 : Device Number

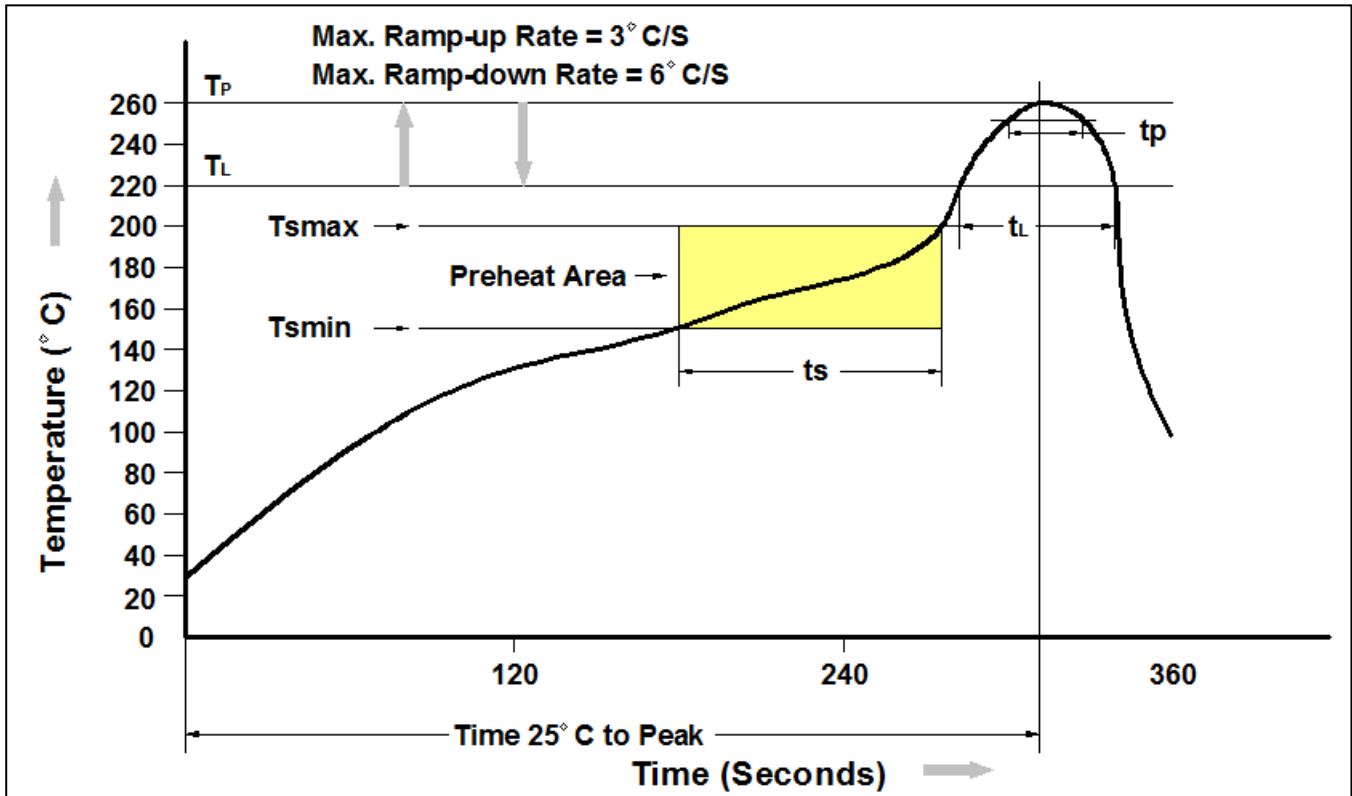
### Ordering Information

<i>Part Number</i>	<i>Description</i>	<i>Quantity</i>
CT2306-R3	SC-59 Reel	3000 pcs





Reflow Profile



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T <sub>min</sub> )	150 °C
Temperature Max. (T <sub>max</sub> )	200 °C
Time (t <sub>s</sub> ) from (T <sub>min</sub> to T <sub>max</sub> )	60-120 seconds
Ramp-up Rate (t <sub>L</sub> to t <sub>P</sub> )	3 °C/second max.
Liquidous Temperature (T <sub>L</sub> )	217 °C
Time (t <sub>L</sub> ) Maintained Above (T <sub>L</sub> )	60 – 150 seconds
Peak Body Package Temperature	260 °C +0 °C / -5 °C
Time (t <sub>P</sub> ) within 5 °C of 260 °C	30 seconds
Ramp-down Rate (T <sub>P</sub> to T <sub>L</sub> )	6 °C/second max
Time 25 °C to Peak Temperature	8 minutes max.



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